

Search Notes

Application/Control No.

10/750,121

Examiner

Hai L. Nguyen

Applicant(s)/Patent under
Reexamination

LIN ET AL.

Art Unit

2816

SEARCHED

Class	Subclass	Date	Examiner
327	172-176, 50-52,56, 63,68,90	2/22/2005	HLN
↓	164	↓	↓
↓	514,515	↓	↓
372	38.02	2/23/2005	
345	39	✓	↓

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Shepardize Search	2/23/2005	HLN